

Notice of References Cited

Application/Control No.

10/020,594

Applicant(s)/Patent Under
Reexamination
SCHREDL ET AL.

Examiner

Len Tran

Art Unit

1725

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,010,060	01-2000	Sarkhel et al.	228/179.1
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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